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Application/Control No.	Applicant(s)/Patent under Reexamination
09/964,237	BATES ET AL.
Examiner	Art Unit
J Derek Rutten	2192

	SEAR	CHED	
Class	Subclass	Date	Examiner
			<u> </u>

INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
			

SEARCH NO (INCLUDING SEARCH)
	DATE	EXMR
EAST (US-PGPUB; USPAT; EPO; JPO; IBM-TDB) - see search history printout	10/7/2005	JDR
EAST (US-PGPUB; USPAT; EPO; JPO; IBM-TDB) - see search history printout	10/10/2005	JDR
ACM - portal.acm.org - see search history printout	10/10/2005	JDR
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